

### Features

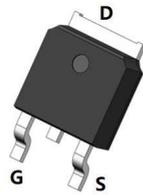
- N-channel SJ MOSFET with deep trench process
- Extremely low losses due to very low Eon and Eoff
- Qualified for industrial grade applications according to JEDEC
- Excellent stability and uniformity

### Application

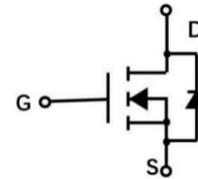
- SMPS
- Adapter
- LED lighting
- EV Charger
- Telecom power
- Solar Inverter

### Key Performance Parameters

Parameter	Value	Unit
V <sub>DS</sub>	650	V
I <sub>D</sub>	14	A
R <sub>DS(ON)_typ</sub>	250	mΩ



TO-252



Equivalent Circuit

**Table 1. Absolute Maximum Ratings (T<sub>C</sub>=25°C unless otherwise specified)**

Symbol	Parameter	Value	Units	
V <sub>GS</sub>	Gate-Source Voltage (static)	±20	V	
V <sub>GS</sub>	Gate-Source Voltage (dynamic)(AC (f>1Hz))	±30		
I <sub>D</sub>	Continuous Drain Current	(T <sub>C</sub> =25°C)	14	A
		(T <sub>C</sub> =100°C)	9	
I <sub>D,pulse</sub>	Pulsed Drain Current (T <sub>C</sub> = 25°C)	25		
I <sub>S</sub>	Continuous diode forward current	(T <sub>C</sub> =25°C)	11	
I <sub>S,pulse</sub>	Diode pulse current	(T <sub>C</sub> =25°C)	25	
E <sub>AS</sub>	Avalanche energy, single pulse(I <sub>D</sub> =3.4A, V <sub>DD</sub> =50 V)	300	mJ	
I <sub>AS</sub>	Avalanche current, single pulse	3.4	A	
dv/dt	MOSFET dv/dt ruggedness (V <sub>DS</sub> =0...400V)	50	V/ns	
dv/dt	Recovery diode dv/dt(V <sub>DS</sub> =0...400V, I <sub>SD</sub> ≤ 7A)	15	V/ns	
P <sub>tot</sub>	Power Dissipation	(T <sub>C</sub> =25°C)	63	W
T <sub>J</sub> , T <sub>STG</sub>	Operating Junction Storage Temperature Range	-55 to +150	°C	

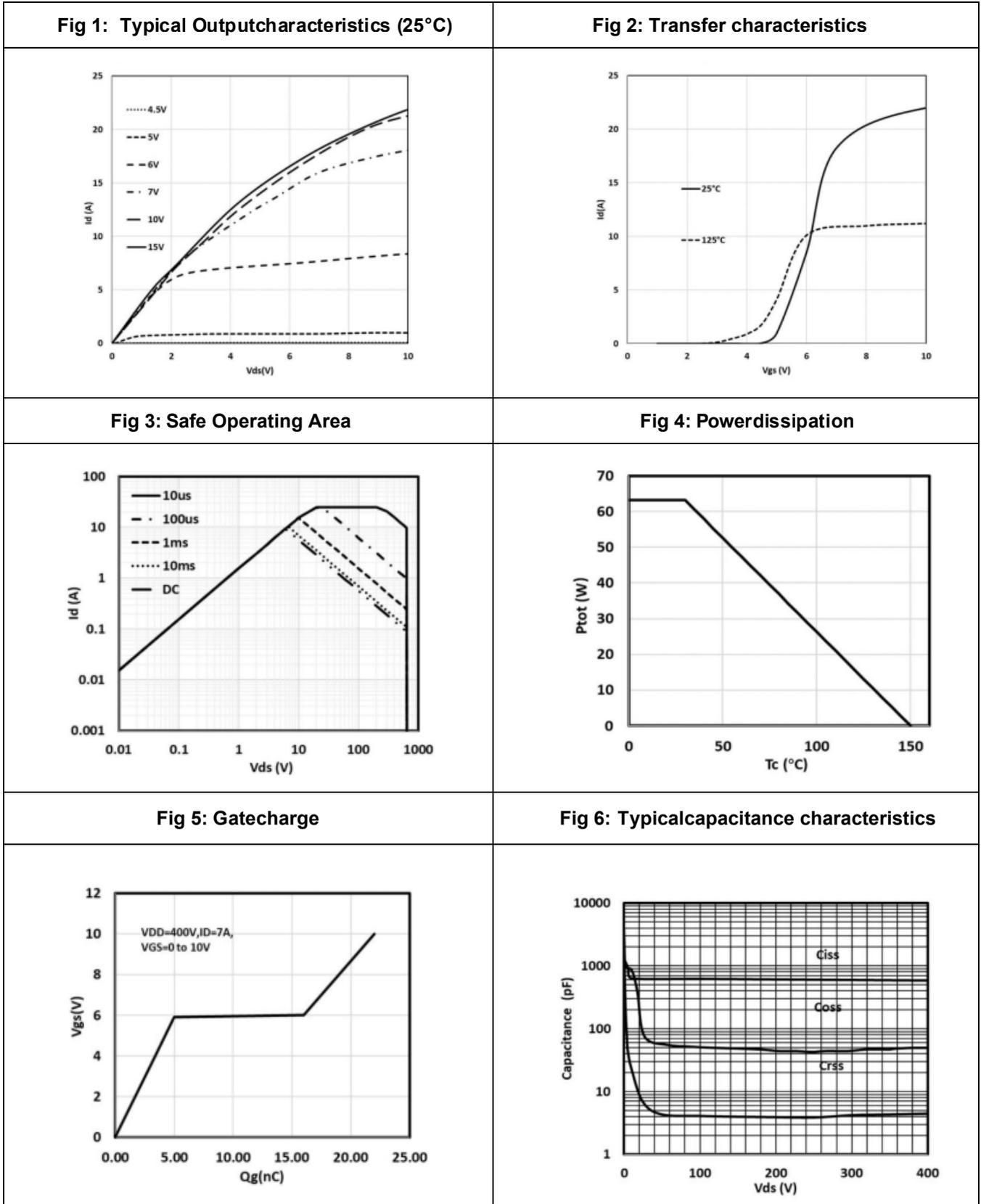
**Table 2. Thermal Characteristic**

Symbol	Parameter	Value			Units
		Min	Typ	Max	
R <sub>thJA</sub>	Thermal resistance, junction - ambient	--	--	62	°C/ W
R <sub>thJC</sub>	Thermal resistance, junction - case	--	--	1.9	°C/ W

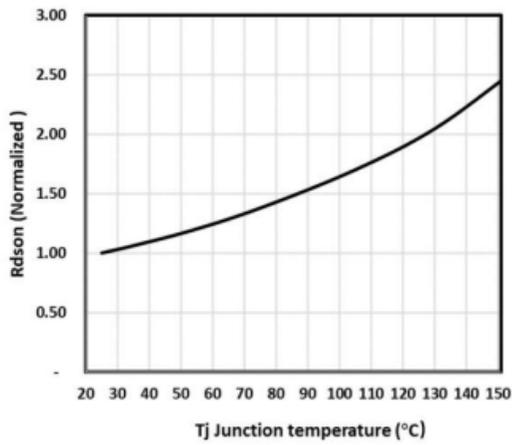
**Table 3. Electrical Characteristics (T<sub>J</sub>=25°C unless otherwise specified)**

Symbol	Parameter	Conditions	Min	Typ	Max	Unit
<b>Static Characteristics</b>						
BV <sub>DSS</sub>	Drain-Source Breakdown Voltage	V <sub>GS</sub> = 0V, I <sub>D</sub> = 1mA	650	--	--	V
V <sub>GS(th)</sub>	Gate Threshold Voltage	V <sub>DS</sub> = V <sub>GS</sub> , I <sub>D</sub> = 250μA	3	3.5	4	V
I <sub>DSS</sub>	Zero Gate Voltage Drain Current	V <sub>DS</sub> = 650V, V <sub>GS</sub> = 0V, T <sub>J</sub> = 25°C	--	--	1	μA
I <sub>GSS</sub>	Gate to Source Leakage Current	V <sub>DS</sub> = 0 V, V <sub>GS</sub> = ±30V	-100	2	100	nA
R <sub>DS(on)</sub>	Drain-Source On-State Resistance	V <sub>GS</sub> = 10V, I <sub>D</sub> = 7A, T <sub>J</sub> = 25°C	--	250	290	mΩ
		V <sub>GS</sub> = 10V, I <sub>D</sub> = 7A, T <sub>J</sub> = 150°C	--	630	--	
R <sub>G</sub>	Gate Resistance	f = 1.0MHz, open drain	--	8	--	Ω
<b>Dynamic Characteristics</b>						
C <sub>iss</sub>	Input Capacitance	V <sub>GS</sub> = 0V, V <sub>DS</sub> = 50V, f = 100kHz	--	450	--	pF
C <sub>oss</sub>	Output Capacitance		--	60	--	
C <sub>rss</sub>	Reverse Transfer Capacitance		--	4.3	--	
t <sub>d(on)</sub>	Turn-on Delay Time	V <sub>DS</sub> = 400 V, I <sub>D</sub> = 7A V <sub>GS</sub> = 15V, R <sub>g</sub> = 10Ω	--	20	--	ns
t <sub>r</sub>	Turn-on Rise Time		--	13	--	
t <sub>d(off)</sub>	Turn-off Delay Time		--	40	--	
t <sub>f</sub>	Turn-off Fall Time		--	15	--	
Q <sub>g</sub>	Total Gate Charge	I <sub>D</sub> = 7 A, V <sub>DD</sub> = 400V V <sub>GS</sub> = 0~10V	--	22	--	nC
Q <sub>gs</sub>	Gate-Source Charge		--	5	--	
Q <sub>gd</sub>	Gate-Drain Charge		--	11	--	
V <sub>plateau</sub>	Gate plateau voltage		--	6	--	V
<b>Body Diode Characteristics</b>						
V <sub>SD</sub>	Body Diode Forward Voltage	V <sub>R</sub> = 400V I <sub>F</sub> = 7 A, diF/dt = 100A/μs,	--	--	1.3	V
t <sub>rr</sub>	Reverse Recovery Time		--	220	--	ns
Q <sub>rr</sub>	Reverse Recovery Charge		--	2.2	--	μC
I <sub>rm</sub>	Peak reverse recovery current		--	16	--	A

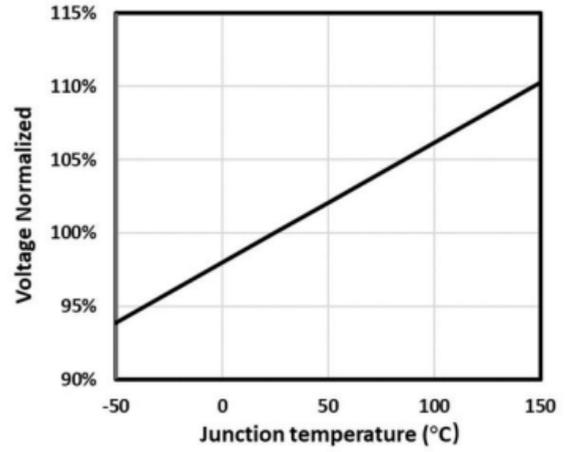
## Typical Electrical and Thermal Characteristics (T<sub>J</sub> = 25°C, unless otherwise noted)



**Fig 7: On Resistor vs.Junction temperature**

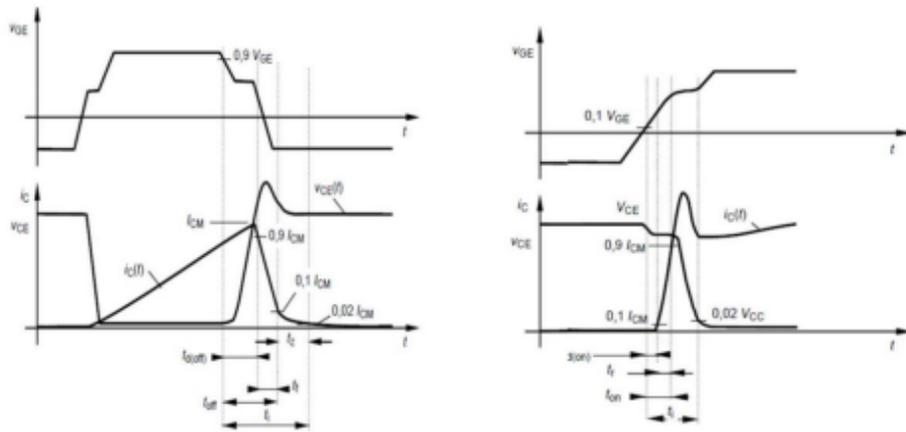


**Fig 8: Drain-Source Breakdown Voltage**



## Test Circuit and Waveforms

**Fig A: Switching Test Circuit & Waveforms**



**Fig B: Diode Recovery Test Circuit & Waveforms**

